

 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 1 of 64

SAR TEST REPORT

Applicant : RM ACQUISITIONS LLC

Address

8770 W. Bryn Mawr Avenue, Chicago, Illinois, United States, 60631

Product Name : GPS Device

ð

Report Date

Sep. 14, 2023



Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Δ

Tel:(86) 0755-26066440 Fax:(86) 0755-

Report No.: 18220WC30188001

FCC ID:A4C-10012A

Page 2 of 64

0 73

www.anbotek.com.cn

Contents

oter.	Statement of Compliance	6
2.	General Information	7
	2.1. Client Information 2.2. Description of Equipment Under Test (EUT)	7
	2.2. Description of Equipment Under Test (EUT)	
	2.3. Device Category and SAR Limits	8
	2.4. Applied Standard	
	2.5. Environment of Test Site	8
	2.6. Test Configuration	8
3.	Specific Absorption Rate (SAR)	
	3. 1. Introduction	
	3. 2. SAR Definition	9
4.	SAR Measurement System	10
	4.1. E-Field Probe	
	4. 2. Data Acquisition Electronics (DAE)	11
	4. 3. Robot	12
	4. 4. Measurement Server	13
	4.5. Phantom	
	4. 6. Device Holder	15
	4.7. Data Storage and Evaluation	16
5.	4. 7. Data Storage and Evaluation Test Equipment List Tissue Simulating Liquids	18
6.	Tissue Simulating Liquids	19
7.	System Verification Procedures	20
8.	System Verification Procedures Measurement Procedures 9. 1. Spatial Peak SAR Evaluation	22
	9.1. Spatial Peak SAR Evaluation	22
	9. 2. Power Reference Measurement	
	9.3. Area Scan Procedures	
	9. 4. Zoom Scan Procedures	
	9. 5. Volume Scan Procedures	25
	9. 6. Power Drift Monitoring	25
9.	Conducted Power	26
10). Antenna Location	28
	10.1 Antenna Location	28
11	.SAR Test Results Summary	29
12	2. Simultaneous Transmission Analysis	30
13	B. Measurement Uncertainty	31
Ap	opendix A. EUT Photos and Test Setup Photos	35
Ap	opendix B. Plots of SAR System Check	36
	zhen Anbotek Compliance Laboratory Limited ss:1/E Building D Sogood Science and Technology Park, Sanwei Community, Hotline	1.406
Hange	ss:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, heng Street, Bao'an District, Shenzhen, Guangdong, China. 6) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com www.anbotek.com.cn	父博 ◎ ● 卿



Report No.: 18220WC30188001	FCC ID:A4C-10012A	Page 3 of 64
Appendix C. Plots of SAR	Test Data	
Appendix D. DASY System	Calibration Certificate	

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 4 of 64

TEST REPORT

Applicant	: RM ACQUISITIONS LLC
Manufacturer	: SHEN ZHEN APICAL TECHNOLOGY CO., LTD
Product Name	: GPS Device
Model No.	: TND750
Trade Mark	RAND MENALLY
Rating(s)	: DC 3.7V from Battery

Test Standard(s) : IEC/IEEE 62209-1528:2020; FCC 47 CFR Part 2.1093; ANSI/IEEE C95.1:2005; Reference FCC KDB 447498; KDB 248227; KDB 616217

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the IEC/IEEE 62209-1528:2020, FCC 47 CFR Part 2.1093, ANSI/IEEE C95.1:2005 and Reference KDB 447498, KDB 248227, KDB 616217 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt Date of Test Aug. 13, 2023 Aug. 13, 2023~ Sep. 04, 2023

Prepared By

Ella Liano

(Ella Liang)

(Kingkong Jin)

Approved & Authorized Signer

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 5 of 64

Version

Version No.	Date	Description		
00	Sep. 14, 2023	Original		
otek anbotek	poboles Anno potek	Anbotek Anbotek Anbotek Anbotek		
obotek Anbotek	Anber hotek Anber	It Anbolen Allen nbotek Anbotek Anbo		
Anbotek Anbote	t anbotek Ant	ofer Anborek Anborek Anbore An		
Anboten Anbo	drek Anbotek	unbolin Anotek Anbotek Anbotek A		
Anbonn An	hbotek Anbotes	Anborek Anbotek Anborek Anborek		

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A

Page 6 of 64

1. Statement of Compliance

The maximum results of Specific Absorption Rate (SAR) found during testing are as follows.

<Highest SAR Summary>

Francisco Dand	Hiç	ghest Reported 1g-	SAR(W/Kg)	SAR Test Limit
Frequency Band	Body(0mm)		(W/Kg)	
WIFI 2.4G	stek anbot	0.226	botek Anboit	1.6
BT	the Hete	0.084	An hotelk Anbote	1.6
Test Result	Ano	abotek Anbois	PASS	oten Anbu wolk

This device is in compliance with Specific Absorption Rate (SAR) for general population/uncontrolled exposure limits (1.6 W/kg) specified in ANSI C95.1:2005, and had been tested in accordance with the measurement methods and procedures specified in IEEE 1528-2013.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-10012A Page 7 of 64

2. General Information

2.1. Client Information

Applicant	:	RM ACQUISITIONS LLC
Address	:	9855 Woods Drive Skokie. IL 60077 U.S.A
Manufacturer	:	SHEN ZHEN APICAL TECHNOLOGY CO., LTD
Address	:	9/F,B Building, Tinghua Unis Infoport, Langshan RD, North district, Hi-tech Industrial Park, Nanshan, Shenzhen

2.2. Description of Equipment Under Test (EUT)

Product Name	:	GPS Device	Anborek Anborek Anborek Anborek Anbor
Model No.	:	TND750	Anborek Anbotek Anborek Anborek Anbor
Trade Mark	:	RAND M?NALLY	otek Anborek Anbore An
Test Power Supply	:	DC 3.7V from Battery	potek Anbole And stek Anbolek
Product		Operation Frequency:	802.11b/ g/ n(HT20): 2412-2462MHz 802.11n(HT40):2422-2452 MHz BT:2402-2480MHz
Description	:	Modulation Type:	802.11b: CCK 802.11g/n: OFDM BT: GFSK, π/4DQPSK, 8DPSK
Remark: 1) For a more detailed features description, please refer to the manufacturer's specifications			

or the User's Manual.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 8 of 64

2.3. Device Category and SAR Limits

This device belongs to portable device category because its radiating structure is allowed to be used within 20 centimeters of the body of the user. Limit for General Population/Uncontrolled exposure should be applied for this device, it is 1.6 W/kg as averaged over any 1 gram of tissue.

2.4. Applied Standard

The Specific Absorption Rate (SAR) testing specification, method, and procedure for this device is in accordance with the following standards:

FCC 47 CFR Part 2.1093

IEC/IEEE 62209-1528:2020

ANSI C95.1:2005

Reference FCC KDB 447498; KDB 248227; KDB 616217

2.5. Environment of Test Site

Items	Required	Actual
Temperature (℃)	18-25	22~23
Humidity (%RH)	30-70	55~65

2.6. Test Configuration

The device was controlled by using a base station emulator. Communication between the device and the emulator was established by air link. The distance between the EUT and the antenna of the emulator is larger than 50 cm and the output power radiated from the emulator antenna is at least 30 dB smaller than the output power of EUT. The EUT was set from the emulator to radiate maximum output power during all tests. For WLAN SAR testing, WLAN engineering testing software installed on the EUT can provide continuous transmitting RF signal.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 9 of 64

3. Specific Absorption Rate (SAR)

3.1. Introduction

SAR is related to the rate at which energy is absorbed per unit mass in an object exposed to a radio field. The SAR distribution in a biological body is complicated and is usually carried out by experimental techniques or numerical modeling. The standard recommends limits for two tiers of groups, occupational/controlled and general population/uncontrolled, based on a person's awareness and ability to exercise control over his or her exposure. In general, occupational/controlled exposure limits are higher limits than the for general population/uncontrolled.

3.2. SAR Definition

The SAR definition is the time derivative (rate) of the incremental energy (dW) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dv) of a given density (ρ).The equation description is as below:

$$SAR = \frac{d}{dt} \left(\frac{dW}{dm} \right) = \frac{d}{dt} \left(\frac{dW}{\rho dv} \right)$$

SAR is expressed in units of Watts per kilogram (W/kg)

SAR measurement can be either related to the temperature elevation in tissue by

$$SAR = C\left(\frac{\delta T}{\delta t}\right)$$

Where: C is the specific head capacity, δT is the temperature rise and δ tisthe exposure duration, or related to the electrical field in the tissue by

$$SAR = \frac{\sigma |E|^2}{\rho}$$

Where: σ is the conductivity of the tissue, ρ is the mass density of the tissue and E is the RMS electrical field strength.

However for evaluating SAR of low power transmitter, electrical field measurement is typically applied.

Shenzhen Anbotek Compliance Laboratory Limited

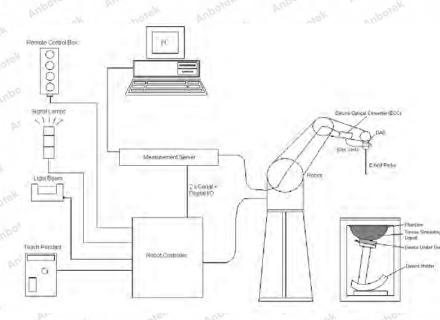
Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 10 of 64

4. SAR Measurement System



DASY System Configurations

The DASY system for performance compliance tests is illustrated above graphically. This system consists of the following items:

- > A standard high precision 6-axis robot with controller, a teach pendant and software
- > A data acquisition electronic (DAE) attached to the robot arm extension
- > A dosimetric probe equipped with an optical surface detector system
- The electro-optical converter (EOC) performs the conversion between optical and electrical signals
- A measurement server performs the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- A probe alignment unit which improves the accuracy of the probe positioning
- A computer operating Windows XP
- DASY software
- Remove control with teach pendant and additional circuitry for robot safety such as warming lamps, etc.
- The SAM twin phantom
- A device holder
- Tissue simulating liquid
- Dipole for evaluating the proper functioning of the system

components are described in details in the following sub-sections.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



Report No.: 18220WC30188001

FCC ID:A4C-10012A

Page 11 of 64

4.1. E-Field Probe

The SAR measurement is conducted with the dosimetric probe (manufactured by SPEAG). The probe is specially designed and calibrated for use in liquid with high permittivity. The dosimetric probe has special calibration in liquid at different frequency. This probe has a built in optical surface detection system to prevent from collision with phantom.

E-Field Probe Specification <EX3DV4 Probe>

Construction	Symmetrical design with triangular core Built-in shielding against static charges PEEK enclosure material (resistant to organic solvents, e.g., DGBE)	
Frequency	10 MHz to 6 GHz; Linearity: ± 0.2 dB	
Directivity	 ± 0.3 dB in HSL (rotation around probe axis) ± 0.5 dB in tissue material (rotation normal to probe axis) 	ANI Chek
Dynamic Range	10 μ W/g to 100 mW/g; Linearity: ± 0.2 dB (noise: typically < 1 μ W/g)	Photo of EX3DV4
Dimensions	Overall length: 330 mm (Tip: 20 mm) Tip diameter: 2.5 mm (Body: 12 mm) Typical distance from probe tip to dipole centers: 1 mm	hbotek Anborek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek

> E-Field Probe Calibration

Each probe needs to be calibrated according to a dosimetric assessment procedure with accuracy better than \pm 10%. The spherical isotropy shall be evaluated and within \pm 0.25dB. The sensitivity parameters (NormX, NormY, and NormZ), the diode compression parameter (DCP) and the conversion factor (ConvF) of the probe are tested. The calibration data can be referred to appendix C of this report.

4.2. Data Acquisition Electronics (DAE)

The data acquisition electronics (DAE) consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the measurement server is accomplished through an optical downlink for data and status information as well as an optical uplink for commands and the clock.

The input impedance of the DAE is 200MOhm; the inputs are symmetrical and floating. Common mode rejection is above 80dB.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 12 of 64



Photo of DAE

4.3. Robot

The SPEAG DASY system uses the high precision robots (DASY5: TX60XL) type from Stäubli SA (France). For the 6-axis controller system, the robot controller version (DASY5: CS8c) from Stäubli is used. The Stäubli robot series have many features that are important for our application:

- > High precision (repeatability ±0.035 mm)
- High reliability (industrial design)
- Jerk-free straight movements
- Low ELF interference (the closed metallic construction shields against motor control fields)



Photo of DASY5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 13 of 64

4.4. Measurement Server

The measurement server is based on a PC/104 CPU board with CPU (DASY5: 400 MHz, Intel Celeron), chip disk (DASY5: 128 MB), RAM (DASY5: 128 MB). The necessary circuits for communication with the DAE electronic box, as well as the 16 bit AD converter system for optical detection and digital I/O interface are contained on the DASY I/O board, which is directly connected to the PC/104 bus of the CPU board.

The measurement server performs all the real-time data evaluation for field measurements and surface detection, controls robot movements and handles safety operations.



Photo of Server for DASY5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A

Page 14 of 64

- 4.5. Phantom
 - <SAM Twin Phantom>

Shell Thickness	2 ± 0.2 mm;	
	Center ear point: 6 ± 0.2 mm	et
Filling Volume	Approx. 25 liters	A 100
Dimensions	Length: 1000 mm; Width: 500 mm; Height: adjustable feet	Ant
Measurement	Left Hand, Right Hand, Flat	
Areas	Phantom	
	tek Anbolek Anbo' Ar	otek Anbor Ar wotek

Photo of SAM Phantom

The bottom plate contains three pair of bolts for locking the device holder. The device holder positions are adjusted to the standard measurement positions in the three sections. A white cover is provided to tap the phantom during off-periods to prevent water evaporation and changes in the liquid parameters. On the phantom top, three reference markers are provided to identify the phantom position with respect to the robot.

<ELI4 Phantom>

2 ± 0.2 mm (sagging: <1%)
Approx. 30 liters
Major ellipse axis: 600 mm
Minor axis:400 mm
porter Anti-horek Antionek Antion
Anborek Anborek Anbore An
and
Photo of ELI4 Phantom

The ELI4 phantom is intended for compliance testing of handheld and body-mounted wireless devices in the frequency range of 30 MHz to 6 GHz. ELI4 is fully compatible with standard and all known tissue simulating liquids.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 15 of 64

4.6. Device Holder

The SAR in the phantom is approximately inversely proportional to the square of the distance between the source and the liquid surface. For a source at 5 mm distance, a positioning uncertainty of ± 0.5 mm would produce a SAR uncertainty of $\pm 20\%$. Accurate device positioning is therefore crucial for accurate and repeatable measurements. The positions in which the devices must be measured are defined by the standards.

The DASY device holder is designed to cope with different positions given in the standard. It has two scales for the device rotation (with respect to the body axis) and the device inclination (with respect to the line between the ear reference points). The rotation center for both scales is the ear reference point (ERP). Thus the device needs no repositioning when changing the angles.

The DASY device holder is constructed of low-loss POM material having the following dielectric parameters: relative permittivity ε = 3 and loss tangent δ = 0.02. The amount of dielectric material has been reduced in the closest vicinity of the device, since measurements have suggested that the influence of the clamp on the test results could thus be lowered.



Device Holder

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



Anbotek Product Safety

FCC ID:A4C-10012A

Page 16 of 64

4.7. Data Storage and Evaluation

Data Storage

The DASY software stores the assessed data from the data acquisition electronics as raw data (in microvolt readings from the probe sensors), together with all the necessary software parameters for the data evaluation (probe calibration data, liquid parameters and device frequency and modulation data) in measurement files. The post-processing software evaluates the desired unit and format for output each time the data is visualized or exported. This allows verification of the complete software setup even after the measurement and allows correction of erroneous parameter settings. For example, if a measurement has been performed with an incorrect crest factor parameter in the device setup, the parameter can be corrected afterwards and the data can be reevaluated.

The measured data can be visualized or exported in different units or formats, depending on the selected probe type (e.g., [V/m], [A/m], [mW/g]). Some of these units are not available in certain situations or give meaningless results, e.g., a SAR-output in a non-lose media, will always be zero. Raw data can also be exported to perform the evaluation with other software packages.

Data Evaluation

The DASY post-processing software (SEMCAD) automatically executes the following procedures to calculate the field units from the microvolt readings at the probe connector. The parameters used in the evaluation are stored in the configuration modules of the software:

Probe parameters:	- Sensitivity	Norm _i , a _{i0} , a _{i1}
	- Conversion factor	ConvFi
	- Diode compression point	dcpi
Device parameters	- Frequency	f f botok
	- Crest factor	cf
Media parameters:	- Conductivity	σ Anton and
	- Density	pret anbo

These parameters must be set correctly in the software. They can be found in the component documents or they can be imported into the software from the configuration files issued for the DASY components. In the direct measuring mode of the multi-meter option, the parameters of the actual system setup are used. In the scan visualization and export modes, the parameters stored in the corresponding document files are used.

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com Hotline 400-003-0500 www.anbotek.com.cn

, ai2





FCC ID:A4C-10012A

Page 17 of 64

The formula for each channel can be given as:

$$\mathbf{V}_{i} = \mathbf{U}_{i} + \mathbf{U}_{i}^{2} \cdot \frac{\mathbf{cf}}{\mathbf{dcp}_{i}}$$

with V_i = compensated signal of channel i, (i = x, y, z)

 U_i = input signal of channel i, (i = x, y, z)

cf = crest factor of exciting field (DASY parameter)

dcp_i = diode compression point (DASY parameter)

From the compensated input signals, the primary field data for each channel can be evaluated:

E-field Probes: $E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$

H-field Probes: $H_i = \sqrt{V_i} \cdot \frac{a_{i0} + a_{i1}f + a_{i2}f^2}{f}$

with V_i = compensated signal of channel i,(i = x, y, z)

Norm_i= sensor sensitivity of channel i, (i = x, y, z), $\mu V/(V/m)^2$ for E-field Probes

ConvF= sensitivity enhancement in solution

a_{ij}= sensor sensitivity factors for H-field probes

f = carrier frequency [GHz]

E_i= electric field strength of channel i in V/m

 H_i = magnetic field strength of channel i in A/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

$$SAR = E_{tot}^2 \cdot \frac{\sigma}{\rho \cdot 1000}$$

with SAR = local specific absorption rate in mW/g

Etot= total field strength in V/m

 σ = conductivity in [mho/m] or [Siemens/m]

 ρ = equivalent tissue density in g/cm³

Note that the density is set to 1, to account for actual head tissue density rather than the density of the tissue simulating liquid.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 18 of 64

5. Test Equipment List

Manufacture	Nome of Equipment	Turne (Mendel		Calib	ration
Manufacturer	Name of Equipment	Type/Model	Serial Number	Last Cal.	Due Date
SPEAG	2450MHz System Validation Kit	D2450V2	910	Jun. 15,2021	Jun. 14,2024
SPEAG	Data Acquisition Electronics	DAE4	387	Sept.06,2022	Sept.05,2023
SPEAG	Dosimetric E-Field Probe	EX3DV4	7396	May 06,2023	May 05,2024
Agilent	ENA Series Network Analyzer	E5071C	MY46317418	Oct.26, 2022	Oct.25, 2023
SPEAG	DAK	DAK-3.5	1226	NCR	NCR
SPEAG	SAM Twin Phantom	QD000P40CD	1802	NCR	NCR
SPEAG	ELI Phantom	QDOVA004AA	2058	NCR	NCR
AR	Amplifier	ZHL-42W	QA1118004	NCR	NCR
Agilent	Power Meter	N1914A	MY50001102	Oct.26, 2022	Oct.25, 2023
Agilent	Power Sensor	N8481H	MY51240001	Oct.26, 2022	Oct.25, 2023
R&S	Spectrum Analyzer	N9020A	MY51170037	Oct.26, 2022	Oct.25, 2023
Agilent	Signal Generation	N5182A	MY48180656	Oct.26, 2022	Oct.25, 2023
Worken	Directional Coupler	0110A05601O-10	COM5BNW1A2	Oct.26, 2022	Oct.25, 2023
YONGFA	Electronic Thermometer	YF-105A	130100325	May 17,2023	May 16,2024
Anbotek	Tissue Simulating Liquids	Body 2450	N/A	NCR	NCR

Note:

- 1. The calibration certificate of DASY can be referred to appendix D of this report.
- 2. The dipole calibration interval can be extended to 3 years with justification. The dipoles are also not physically damaged, or repaired during the interval.
- 3. The Insertion Loss calibration of Dual Directional Coupler and Attenuator were characterized via the network analyzer and compensated during system check.
- 4. The dielectric probe kit was calibrated via the network analyzer, with the specified procedure (calibrated in pure water) and calibration kit (standard) short circuit, before the dielectric measurement. The specific procedure and calibration kit are provided by Agilent.
- 5. In system check we need to monitor the level on the power meter, and adjust the power amplifier level to have precise power level to the dipole; the measured SAR will be normalized to 1W input power according to the ratio of 1W to the input power to the dipole. For system check, the calibration of the power amplifier is deemed not critically required for correct measurement; the power meter is critical and we do have calibration for it

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 19 of 64

6. Tissue Simulating Liquids

For the measurement of the field distribution inside the SAM phantom with DASY, the phantom must be filled with around 25 liters of homogeneous body tissue simulating liquid. For head SAR testing, the liquid height from the ear reference point (ERP) of the phantom to the liquid top surface is larger than 15 cm, which is shown in Fig. 6.1. For body SAR testing, the liquid height from the center of the flat phantom to the liquid top surface is larger than 15 cm, which is shown as followed:





Photo of Liquid Height for Head SAR

Photo of Liquid Height for Body SAR

Measured	Target	Tissue		Measure	d Tissue		Liquid	
Frequency (MHz)	٤r	σ	٤r	Dev. (%)	σ	Dev. (%)	Liquid Temp.	Test Data
2450	52.7	1.95	54.028	2.52%	1.999	2.51%	22.3	08/15/2023

The following table shows the measuring results for simulating liquid.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



Anbotek Product Safety

FCC ID:A4C-10012A

Page 20 of 64

7. System Verification Procedures

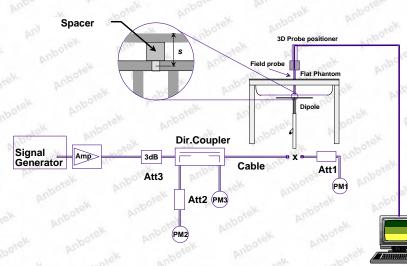
Each DASY system is equipped with one or more system validation kits. These units, together with the predefined measurement procedures within the DASY software, enable the user to conduct the system performance check and system validation. System validation kit includes a dipole, tripod holder to fix it underneath the flat phantom and a corresponding distance holder.

Purpose of System Performance check

The system performance check verifies that the system operates within its specifications. System and operator errors can be detected and corrected. It is recommended that the system performance check be performed prior to any usage of the system in order to guarantee reproducible results. The system performance check uses normal SAR measurements in a simplified setup with a well characterized source. This setup was selected to give a high sensitivity to all parameters that might fail or vary over time. The system check does not intend to replace the calibration of the components, but indicates situations where the system uncertainty is exceeded due to drift or failure.

System Setup

In the simplified setup for system evaluation, the EUT is replaced by a calibrated dipole and the power source is replaced by a continuous wave that comes from a signal generator. The calibrated dipole must be placed beneath the flat phantom section of the SAM twin phantom with the correct distance holder. The distance holder should touch the phantom surface with a light pressure at the reference marking and be oriented parallel to the long side of the phantom. The equipment setup is shown below:



System Setup for System Evaluation

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 21 of 64



Photo of Dipole Setup

Validation Results

Comparing to the original SAR value provided by SPEAG, the verification data should be within its specification of 10%. The table below shows the target SAR and measured SAR after normalized to 1W input power. It indicates that the system performance check can meet the variation criterion and the plots can be referred to Appendix B of this report.

Date	Frequency (MHz)	Power fed onto reference dipole (mW)	Targeted SAR (W/kg)	Measured SAR (W/kg)	Normalized SAR (W/kg)	Deviation (%)
08/15/2023	2450	250	51.8	12.43	49.72	-4.02%

Target and Measurement SAR after Normalized

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 22 of 64

8. Measurement Procedures

The measurement procedures are as follows:

- (a) Use base station simulator (if applicable) or engineering software to transmit RF power continuously (continuous Tx) in the middle channel.
- (b) Keep EUT to radiate maximum output power or 100% duty factor (if applicable)
- (c) Measure output power through RF cable and power meter.
- (d) Place the EUT in the positions as setup photos demonstrates.
- (e) Set scan area, grid size and other setting on the DASY software.
- (f) Measure SAR transmitting at the middle channel for all applicable exposure positions.
- (g) Identify the exposure position and device configuration resulting the highest SAR
- (h) Measure SAR at the lowest and highest channels at the worst exposure position and device configuration if applicable.

According to the test standard, the recommended procedure for assessing the peak spatial-average SAR value consists of the following steps:

- (a) Power reference measurement
- (b) Area scan
- (c) Zoom scan
- (d) Power drift measurement

9.1. Spatial Peak SAR Evaluation

The procedure for spatial peak SAR evaluation has been implemented according to the test standard. It can be conducted for 1g and 10g, as well as for user-specific masses. The DASY software includes all numerical procedures necessary to evaluate the spatial peak SAR value.

The base for the evaluation is a "cube" measurement. The measured volume must include the 1g and 10g cubes with the highest averaged SAR values. For that purpose, the center of the measured volume is aligned to the interpolated peak SAR value of a previously performed area scan.

The entire evaluation of the spatial peak values is performed within the post-processing engine (SEMCAD). The system always gives the maximum values for the 1g and 10g cubes. The algorithm to find the cube with highest averaged SAR is divided into the following stages:

- (a) Extraction of the measured data (grid and values) from the Zoom Scan
- (b) Calculation of the SAR value at every measurement point based on all stored data (A/D values and measurement parameters)
- (c) Generation of a high-resolution mesh within the measured volume
- (d) Interpolation of all measured values form the measurement grid to the high-resolution grid
- (e) Extrapolation of the entire 3-D field distribution to the phantom surface over the distance from Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 23 of 64

sensor to surface

(f) Calculation of the averaged SAR within masses of 1g and 10g

9.2. Power Reference Measurement

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to phantom surface. This distance cannot be smaller than the distance of sensor calibration points to probe tip as defined in the probe properties.

9.3. Area Scan Procedures

The area scan is used as a fast scan in two dimensions to find the area of high field values, before doing a fine measurement around the hot spot. The sophisticated interpolation routines implemented in DASY software can find the maximum found in the scanned area, within a range of the global maximum. The range (in dB0 is specified in the standards for compliance testing. For example, a 2 dB range is required in IEEE standard 1528 and IEC 62209 standards, whereby 3 dB is a requirement when compliance is assessed in accordance with the ARIB standard (Japan), if only one zoom scan follows the area scan, then only the absolute maximum will be taken as reference. For cases where multiple maximums are detected, the number of zoom scans has to be increased accordingly.

Area scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

	\leq 3 GHz	> 3 GHz
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface	5 ± 1 mm	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5 \text{ mm}$
Maximum probe angle from probe axis to phantom surface normal at the measurement location	$30^{\circ} \pm 1^{\circ}$	$20^{\circ} \pm 1^{\circ}$
	\leq 2 GHz: \leq 15 mm 2 - 3 GHz: \leq 12 mm	$3 - 4 \text{ GHz} \le 12 \text{ mm}$ $4 - 6 \text{ GHz} \le 10 \text{ mm}$
Maximum area scan spatial resolution: Δx_{Area} , Δy_{Area}	When the x or y dimension of measurement plane orientation the measurement resolution in x or y dimension of the test of measurement point on the test	on, is smaller than the above, must be \leq the corresponding levice with at least one

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 24 of 64

9.4. Zoom Scan Procedures

Zoom scans are used assess the peak spatial SAR values within a cubic averaging volume containing 1 gram and 10gram of simulated tissue. The zoom scan measures points (refer to table below) within a cube shoes base faces are centered on the maxima found in a preceding area scan job within the same procedure. When the measurement is done, the zoom scan evaluates the averaged SAR for 1 gram and 10 gram and displays these values next to the job's label. Zoom scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

			\leq 3 GHz	⇒ 3 GHz
Maximum zoom scan s	patial reso	olution: Δx _{Zoom} , Δy _{Zoom}	$\leq 2 \text{ GHz}: \leq 8 \text{ mm}$ 2 - 3 GHz: $\leq 5 \text{ mm}^*$	$3 - 4 \text{ GHz:} \le 5 \text{ mm}^*$ $4 - 6 \text{ GHz:} \le 4 \text{ mm}^*$
	uniform	grid: ∆z _{Zoom} (n)	≤ 5 mm	$3 - 4 \text{ GHz} \le 4 \text{ mm}$ $4 - 5 \text{ GHz} \le 3 \text{ mm}$ $5 - 6 \text{ GHz} \le 2 \text{ mm}$
Maximum zoom scan spatial resolution, normal to phantom surface	1 st two points closest		\leq 4 mm	3 – 4 GHz: ≤3 mm 4 – 5 GHz: ≤2.5 mm 5 – 6 GHz: ≤2 mm
	grid	∆z _{Zoom} (n>1): between subsequent points	$\leq 1.5 \cdot \Delta$	Z _{Zoom} (n-1)
Minimum zoom scan volume	x, y, z		≥ 30 mm	$3 - 4 \text{ GHz} \ge 28 \text{ mm}$ $4 - 5 \text{ GHz} \ge 25 \text{ mm}$ $5 - 6 \text{ GHz} \ge 22 \text{ mm}$

Note: δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details.

When zoom scan is required and the <u>reported</u> SAR from the area scan based 1-g SAR estimation procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



FCC ID:A4C-10012A

Page 25 of 64

9.5. Volume Scan Procedures

The volume scan is used for assess overlapping SAR distributions for antennas transmitting in different frequency bands. It is equivalent to an oversized zoom scan used in standalone measurements. The measurement volume will be used to enclose all the simultaneous transmitting antennas. For antennas transmitting simultaneously in different frequency bands, the volume scan is measured separately in each frequency band. In order to sum correctly to compute the 1g aggregate SAR, the EUT remain in the same test position for all measurements and all volume scan use the same spatial resolution and grid spacing. When all volume scan were completed, the software, SEMCAD postprocessor can combine and subsequently superpose these measurement data to calculating the multiband SAR.

9.6. Power Drift Monitoring

All SAR testing is under the EUT install full charged battery and transmit maximum output power. In DASY measurement software, the power reference measurement and power drift measurement procedures are used for monitoring the power drift of EUT during SAR test. Both these procedures measure the field at a specified reference position before and after the SAR testing. The software will calculate the field difference in dB. If the power drift more than 5%, the SAR will be retested.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 26 of 64

9. Conducted Power

Mode	Channel	Frequency (MHz)	Conducted Power (dBm)	Tune-up(dBm)
	1 Jek	2412	13.91	15.0
802.11b	6	2437	14.72	15.0
	stek 11 nbo	2462	14.53	15.0
	stek 1 sabore	2412	11.45	12.0
802.11g	6	2437	11.22	12.0
-	11 ACT	2462	11.89	12.0
	1	2412	10.82	12.0
802.11n(20MHz)	6	2437	10.56	12.0
	11	2462	11.37	12.0
	3	2422	12.32	13.0
802.11n(40MHz)	6	2437	12.56	13.0
	solet 9 price	2452	12.71	13.0

<WIFI 2.4GHz Conducted Power>

Note:

1. Per KDB 447498 D01, the 1-g SAR test exclusion thresholds for 100 MHz to 6 GHz at *test separation distances* ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance,

mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation

The result is rounded to one decimal place for comparison

ip'	Mode	Frequency (GHz)	Tune-up Power (dBm)	Max. Power (mW)	Test distance (mm)	Result	exclusion thresholds for 1-g SAR
	802.11b	2.437	15.0	31.62	et 5 potek	9.9	3.0

2. Base on the result of note1, RF exposure evaluation of 802.11 b mode is required.

- 3. Per KDB 248227 D01, choose the highest output power channel to test SAR and determine further SAR exclusion.
- 4. Per KDB 248227 D01, In the 2.4 GHz band, separate SAR procedures are applied to DSSS and OFDM configurations to simplify DSSS test requirements. SAR is not required for the following 2.4 GHz OFDM conditions:

1) When KDB Publication 447498 SAR test exclusion applies to the OFDM configuration.

2) When the highest reported SAR for DSSS is adjusted by the ratio of OFDM to DSSS specified maximum output power and the adjusted SAR is \leq 1.2 W/kg.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 <Bluetooth Conducted Power>

FCC ID:A4C-10012A

Page 27 of 64

Mode	Channel	Frequency (MHz)	Conducted Average Power (dBm)	Tune-up(dBm)	
	00	2402	-0.10	1.00	
GFSK	39	2441	0.68	1.00	
	78	2480	0.99	1.00	
	00	2402	1.67	3.00	
π/4DQPSK	39	2441	2.17	3.00	
	78	2480	2.69	3.00	
	00	2402	1.97	3.00	
8DPSK	39	2441	2.58	3.00	
	78	2480	2.98	3.00	

The Gain of the ant is 1.61dBi

	;	Standalone	e SAR test	exclusion	on consic	lerations		
Modulation	Frequency (MHz)	Configuration	Maximum Average Power (dBm)	Maximum EIRP (dBm)	Maximum EIRP (mW)	Separation Distance (mm)	SAR Exclusion Thresholds (mW)	Standalone SAR Exclusion
WIFI(802.11b)	2450	Body*	15.0	16.61	45.81	5	Antonia 4	No
BT(GFSK)	2480	Body*	3.00	4.61	2.89	Anio 5	Anbo 4 stek	Yes

Estimated SAR for Bluetooth

Desition	£ (CU-)	Distance	Upper lim	it of power *	Estimated _{1g}
Position	f (GHz)	(mm)	dBm	mW	(W/kg)
Body	2.480	5	3.00	1.995	0.084

* - Maximum possible output power declared by manufacturer

When standalone SAR test exclusion applies to an antenna that transmits simultaneously with other antennas, the standalone SAR must be estimated according to following to determine simultaneous transmission SAR test exclusion:

(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)]·[$\sqrt{f(GHz)/x}$] W/kg for test separation distances ≤ 50 mm;

Where x = 7.5 for 1-g SAR.

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com

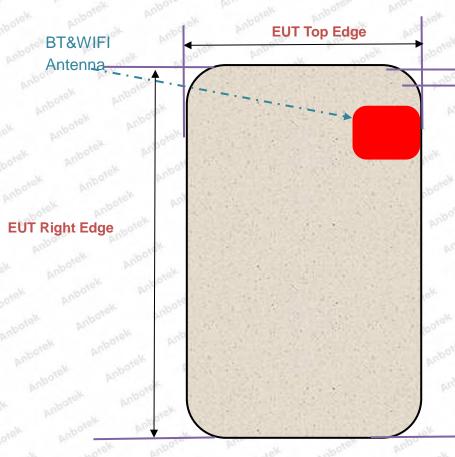




 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 28 of 64

10. Antenna Location

10.1 Antenna Location



EUT Bottom Edge

Distance of The Antenna to the EUT surface and edge							
Antennas Front Back Top Side Bottom Side Left Side Right Side							
WLAN <5mm							

Positions for SAR tests; Hotspot mode									
Antennas Front Back Top Side Bottom Side Left Side Right Side									
WLAN	Yes	Yes	YES	No	YES	No			
Neter	and the solution of the soluti								

Note:

1). According to the KDB941225 D06 Hot Spot SAR v02, the edges with less than 2.5 cm distance to the antennas need to be tested for SAR.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com Hotline 400-003-0500 www.anbotek.com.cn

EUT Left Edge





FCC ID:A4C-10012A

Page 29 of 64

11. SAR Test Results Summary

General Note:

1. Per KDB 447498 D01v05r01, the reported SAR is the measured SAR value adjusted for maximum tune-up tolerance.

Scaling Factor = tune-up limit power (mW) / EUT RF power (mW), where tune-up limit is the maximum rated power among all production units.

- Reported SAR(W/kg)= Measured SAR(W/kg)* Scaling Factor
- 2. Per KDB 447498 D01v05r01, for each exposure position, if the highest output channel reported SAR≤0.8W/kg, other channels SAR testing are not necessary

<WIFI 2.4GHz>

Plot No.	Band	Mode	Test Position	Gap (cm)	Ch.	Freq. (MHz)	Fower	Tune-Up Limit (dBm)	Scaling Factor	JAR1a	Reported SAR _{1g} (W/kg)
#1	WIFI 2.4GHz	802.11b	Front	0	6	2437	14.72	15.00	1.067	0.171	0.182
P	WIFI 2.4GHz	802.11b	Rear	0	6	2437	14.72	15.00	1.067	0.212	0.226
	WIFI 2.4GHz	802.11b	Left Side	0	6	2437	14.72	15.00	1.067	0.187	0.200
ton.	WIFI 2.4GHz	802.11b	Right Side	0	6	2437	14.72	15.00	1.067		w pat
botak	WIFI 2.4GHz	802.11b	Top Side	0	6	2437	14.72	15.00	1.067	0.042	0.045
-100	WIFI 2.4GHz	802.11b	Bottom Side	0	6	2437	14.72	15.00	1.067	- Pur	unter.

			WLAN- S	Scaled Reported	SAR			
		Fre	quency		mavimum	Departed CAD	Scaled	
Mode	Test Position	СН	MHz	Actual duty factor	maximum duty factor	Reported SAR (1g)(W/kg)	reported SAR (1g)(W/kg)	
00. V-	Front	6	2437	99.81%	100%	0.182	0.182	
000 111	Rear	6 oher	2437	99.81%	100%	0.226	0.226	
802.11b	Left Side	6 00	2437	99.81%	100%	0.200	0.200	
suboli	Top Side	6	2437	99.81%	100%	0.045	0.045	

Note: Appendix C. Plots of SAR Test Data

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 30 of 64

12. Simultaneous Transmission Analysis

WIFI 2.4GHz and Bluetooth share the same antenna, and can not transmit simultaneously.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 31 of 64

13. Measurement Uncertainty

1	W hover	Ano		Hat	- abo	9-	print	ind	BL
NO	Source	Uncert. ai(%)	Prob. Dist.	Div. k	ci (1g)	ci (10g)	Stand.U ncert. ui (1g)	Stand.U ncert. ui (10g)	Veff
do	hek Anbone An-	Lotek	anboten	Put	Hay		botek	Anboto	
1 nbr	Repeat	0.4	Notek	1	pho 1	1	0.4	0.4	9 10
P	nu abotek Anbotek	Anbo,	Instru	iment	Aupol	No.	Anthotek	Aupotr	2H
2	Probe calibration	7	Ne ^N N P	2	1	1	3.5	3.5 Ant	8
(3.bo	Axial isotropy	4.7	Anbotek Rk		0.7	0.7	1.9	1.9	A100
4	Hemispherical isotropy	9.4	Runbo	√3	0.7	0.7	3.9	3.9	8
5	Boundary effect	1.0	R	√3	1	anbotek	0.6	0.6	n b ^{ort} ∞
6	Linearity	4.7	R	√3	nbotek	1 An	2.7	2.7	8
7	Detection limits	1.0	Ruiboli	√3	Anbote 1	ove ^V 1	0.6	0.6	Nel 8
8	Readout electronics	0.3 1000	N Ant	1,et	1	mbglak	0.3	0.3	∞
9	Response time	0.8	R	√ <u>3</u>	lok 1	Anboti 1	0.5	0.5	Anbore
10	Integration time	2.6	Anbotek R bote	√3	Antagtel	1	1.5 K	Anbote 1.5 otek	8
11	Ambient noise	3.0	R Anb	√3	1	ho'I'	1.7	1.7	8
12	Ambient reflections	3.0	ofer R	√3	1	Anbote 1	and 1.7	1.7	Anbotel 00
13	Probe positioner mech. restrictions	0.4	R	√3	potek pribotek	1 P	0.2	0.2	8 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



eport N	lo.: 18220WC30188001	FCC ID	:A4C-1001	2A	Page 32 of 64			
14	Probe positioning with respect to phantom shell	2.9	Rindstalt	√3 1	Anbote 1Anb	1.7	1.7	Anbored
15	Max.SAR evaluation	Anbotek 1.0 Anbotek	Anbore R Anbo	1 √31	Albort14	0.6	0.6	oster 8

Anb	totek Anbolek p	nbotek	Test samp	ole rela	ted	P	nbotek	Anbotek	pinbo
16	Device positioning	3.8	N Anbo	14 14	1 An	0 ⁰¹⁰ 1	3.8	3.8	99
17	Device holder	5.1	thotelN	pri2 ote	1	Anbolet 1	5.1	5.1	Srek
18	Drift of output power	5.0	Anboten Rotek	√3	mbotek 1	1	2.9	2.9	~
P	Anbotett Anbotet	Anutotek	Phantom a	and set	t-up	Make	Anbotek	Anbote	ng Har
19	Phantom uncertainty	4.0	R	√3	1	pnbotek 1	2.3	2.3	
20	Liquid conductivity (target)	5.0	Anborek R Anborek	√3	0.64	0.43	1.8	1.2	∞
21	Liquid conductivity (meas)	2.5	Anborr	o ^{ve} 1	0.64	0.43	1.6	1.2	œ
22	Liquid Permittivity (target)	5.0	AUD- POK	√3	0.6	0.49	1.7	1.5	Nr ¹⁰ ∞
23	Liquid Permittivity (meas)	2.5	Nrbote	1	0.6	0.49	1.5	1.2	00 00
Here K	Combined standard	Anboth	RSS	U _c	$=\sqrt{\sum_{i=1}^{n}C}$	${_{i}}^{2}U_{i}^{2}$	11.4%	11.3%	236
unc	Expanded certainty(P=95%)	otek pro	Anbotek U	$J_c = k U$,k=2	2 Anto	22.8%	22.6%	Anburg

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



Report No.: 18220WC30188001

FCC ID:A4C-10012A

Page 33 of 64

No.	Error Description	Uncertainty Value	Probably Distribution	Div.	(Ci) 1g	(Ci) 10g	Std. Unc. (1g)	Std. Unc. (10g)	Degree of freedom
Measureme	nt System	Anbor	put		aboten	buy	- No	hotek	Anbor
+ 1 05	Probe calibration	6.05%	Nabo	1	1	1	6.05%	6.05%	∞
2	Axial isotropy	0.00%	otek R Anbo	$\sqrt{3}$	0.7	0.7	0.00%	0.00%	œ
3	Hemispherical isotropy	0.00%	botek R M	$\sqrt{3}$	0.7	0.7	0.00%	0.00%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
4 tek	Boundary Effects	0.00%	R	$\sqrt{3}$	1	no 1	0.00%	0.00%	8
5	Probe Linearity	0.00%	R	$\sqrt{3}$	1	PUD	0.00%	0.00%	Anbon
6	System Detection Limits	0.00%	R	$\sqrt{3}$	looten	1AnD	0.00%	0.00%	<u>p</u> ()∞
7 Ant	Modulation response	0.00%	R	$\sqrt{3}$	pri10ter	1	0.00%	0.00%	*/ ⁰⁰
8	Readout electronics	0.00%	N	otel-	Anbr	1 ¹⁰¹¹	0.00%	0.00%	00 p.
9	Response time	0.00%	R Pr	$\sqrt{3}$	1	100'P	0.00%	0.00%	
10	Integration time	0.00%	R	$\sqrt{3}$	1	Lotel	0.00%	0.00%	∞
P 11	RF Ambient Noise	0.00%	R	$\sqrt{3}$	1	1	0.00%	0.00%	AND 00
12	RF Ambient Reections	0.00%	R	$\sqrt{3}$	ooter 1	1 mbr	0.00%	0.00%	∞
13	Probe Positioner	0.02%	R	$\sqrt{3}$	pliet	1 🕅	0.01%	0.01%	∞ 00
a ^w 14	Probe Positioning	0.40%	R Anbo	$\sqrt{3}$	1	et 1	0.23%	0.23%	∞
15	Max. SAR Eval.	0.00%	otek R ant	$\sqrt{3}$	1	14	0.00%	0.00%	∞
System cheo	ck source (dipole)	those by	the	boten	ps	100.		tet ant	polon
16	Dev. of experimental dipole	0.00%	Anbo N	1,00	* 1	Antigoto	0.00%	0.00%	nbotem
170010	Dipole Axis to Liquid Dist.	2.00%	P ^{rib} R	$\sqrt{3}$	otet	Anbo	1.15%	1.15%	and where
18	Input power & SAR drift	5.00%	R	$\sqrt{3}$	boliek	1 p.	2.89%	2.89%	× oot
Phantom an	d Setup	the most	ex phipo,	-	p.	40	anbolen.	Pun	N
19	Phantom uncertainty	7.20%	stell R sold	$\sqrt{3}$	M	1	4.16%	4.16%	∞
20	SAR correction	0.00%	N	bolet	1 pr	0.84	0.00%	0.00%	∞
21	Liquid conductivity (meas.)	2.50%	N N	Love	0.78	0.71	1.95%	1.78%	nbonek.
22	Liquid permittivity (meas.)	2.50%	Anbon N	1	0.23	0.26	0.58%	0.65%	8
23	Temp. unc Conductivity	3.60%	R	$\sqrt{3}$	0.78	0.71	1.62%	1.48%	× option
24	Temp. unc Permittivity	0.50%	Ranbon	$\sqrt{3}$	0.23	0.26	0.07%	0.08%	∞
Cor	nbined standard unce	rtainty	RSS prof		bu.	Agek	8.65%	8.57%	A.
Expanded	uncertainty (confiden	ce interval of	K=2	Loter	p.m	Ask	17.30%	17.14%	6 P. P.

leasurement uncertainty evaluation for System Check (0.3-3GHz)

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



No.	Error Description	Uncertainty Value	Probably Distribution	Div.	(Ci) 1g	(Ci) 10g	Std. Unc. (1g)	Std. Unc. (10g)	Degree of freedom
Measuremer	nt System	pinon	hotek	phi	Jour	bu	Aek.	aboter	Ano
1pnbo	Probe calibration	6.65%	N	1	abole*	1 pm	6.65%	6.65%	8
2	Axial isotropy	0.00%	R	$\sqrt{3}$	0.7	0.7	0.00%	0.00%	∞
ate* 3	Hemispherical isotropy	0.00%	otek R Anbc	$\sqrt{3}$	0.7	0.7	0.00%	0.00%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
4	Boundary Effects	0.00%	ntootak R A	$\sqrt{3}$	1	bolek	0.00%	0.00%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
5 tet	Probe Linearity	0.00%	R	$\sqrt{3}$	1	1 note	0.00%	0.00%	∞
6	System Detection Limits	0.00%	R	$\sqrt{3}$	1	1	0.00%	0.00%	∞ ∞
7	Modulation response	0.00%	Robertek	$\sqrt{3}$	1001	1	0.00%	0.00%	∞
8	Readout electronics	0.00%	N N N	1	potore	1	0.00%	0.00%	8
9	Response time	0.00%	R	$\sqrt{3}$	Inb	1	0.00%	0.00%	00 p.01
10	Integration time	0.00%	R P	$\sqrt{3}$	1	bolt	0.00%	0.00%	00 ¹⁰¹ 00
11 vet	RF Ambient Noise	0.00%	R	$\sqrt{3}$	1	1 de	0.00%	0.00%	∞
12	RF Ambient Reections	0.00%	R	$\sqrt{3}$	1	1	0.00%	0.00%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
13	Probe Positioner	0.04%	R	$\sqrt{3}$	001	1	0.02%	0.02%	8
14 Anb	Probe Positioning	0.80%	R	$\sqrt{3}$	ablet	1 🕅	0.46%	0.46%	∞
e ^x 15	Max. SAR Eval.	0.00%	R M	$\sqrt{3}$	1	let 1	0.00%	0.00%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
System chec	k source (dipole)		water and	DOIN	be.	19ac	aboten	PUDA	y.
16	Dev. of experimental dipole	0.00%	N	anbottek	1 1	1 1 sek	0.00%	0.00%	~~~~
17	Dipole Axis to Liquid Dist.	2.00%	R	$\sqrt{3}$	1	Anto	1.15%	1.15%	00
18	Input power & SAR drift	5.00%	Ant R	$\sqrt{3}$	potel	1nbo	2.89%	2.89%	8
Phantom and	d Setup	anboter	Punn	80	botek	pi	100.	Par stelk	nabote
19	Phantom uncertainty	7.60%	R prot	$\sqrt{3}$	1	e¥ 1	4.39%	4.39%	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~
20	SAR correction	0.00%	oself N port	1	1	0.84	0.00%	0.00%	∞
21	Liquid conductivity (meas.)	2.50%	N	nbolek	0.78	0.71	1.95%	1.78%	∞
22	Liquid permittivity (meas.)	2.50%	N	anaor	0.23	0.26	0.58%	0.65%	œ
23	Temp. unc Conductivity	3.60%	R	$\sqrt{3}$	0.78	0.71	1.62%	1.48%	8
24	Temp. unc Permittivity	0.50%	R	$\sqrt{3}$	0.23	0.26	0.07%	0.08%	8
14	bined standard unce	y. both	RSS		Anbot	Nº-	9.25%	9.18%	60.

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





 Report No.: 18220WC30188001
 FCC ID:A4C-10012A
 Page 35 of 64

Appendix A. EUT Photos and Test Setup Photos



Body Front(0mm)



Body Back(0mm)



Top (0mm)



Left(0mm)

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 36 of 64

Appendix B. Plots of SAR System Check

Date: 08/15/2023

DUT: Dipole 2450 MHz; Type: D2450V2; Serial: 910

Communication System: CW; Frequency: 2450 MHz;Duty Cycle: 1:1 Medium parameters used (interpolated): f = 2450 MHz; σ = 1.999 S/m; ϵ r = 54.028; ρ = 1000 kg/m3 Phantom section: Flat Section

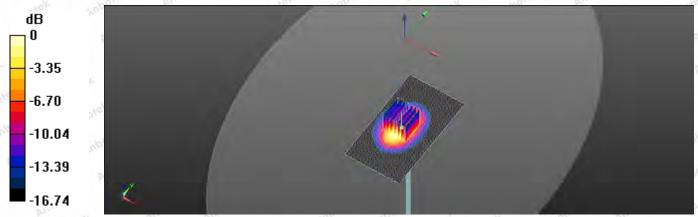
DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(7.53, 7.53, 7.53); Calibrated: 05,06.2023;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06.2022
- Phantom: SAM; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

Area Scan (51x61x1): Interpolated grid: dx=12 mm, dy=12 mm Maximum value of SAR (interpolated) = 22.0 W/kg Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm Reference Value = 99.08 V/m; Power Drift = 0.04 dB Peak SAR (extrapolated) = 27.40 W/kg

SAR(1 g) = 12.43 W/kg; SAR(10 g) = 6.09 W/kg

Maximum value of SAR (measured) = 20.3 W/kg



0 dB = 20.3 W/kg = 13.07 dBW/kg

System Performance Check 2450MHz 250mW

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 37 of 64

Appendix C. Plots of SAR Test Data

#1

WIFI 2.4G_802.11b_ Rear_Ch6

Communication System: UID 0, Generic WIFI (0); Frequency: 2437 MHz; Medium parameters used: f = 2437 MHz; σ = 2.015 S/m; ϵ r = 54.178; ρ = 1000 kg/m3 Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(9.82, 9.82, 9.82); Calibrated: 05,06.2023;
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06,2022;
- Phantom: SAM 1; Type: SAM;
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

Rear/CH 6/Area Scan (131x151x1): Interpolated grid: dx=1.200 mm, dy=1.200 mm Maximum value of SAR (interpolated) = 0.265W/kg

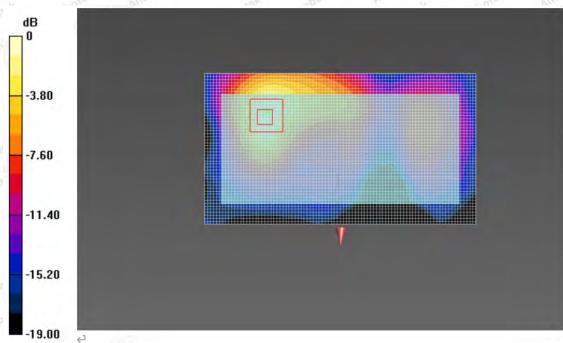
Rear/CH 6/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 5.01 V/m; Power Drift = -0.02 dB

Peak SAR (extrapolated) = 0.292 W/kg

SAR(1 g) = 0.212 W/kg; SAR(10 g) = 0.141W/kg

Maximum value of SAR (measured) = 0.222 W/kg



Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A



Appendix D. DASY System Calibration Certificate

		at. Beijing, 100191, China	CALIBRATI CNAS L053
Tel: +86-10-623046 E-mail: cul@chinatt		i-10-62304633-2209	
Client Anb	otek (Auden)	Certificate No: Z23-	98671
CALIBRATION CE	RTIFICATE		
Dbject	EX3DV4	- SN:7396	
Calibration Procedure(s)	EE 742 0	06-08	
	FF-Z12-0 Calibratio	006-08 on Procedures for Dosimetric E-field Probes	
Calibration date:	May 06, 2		
11 march 11 12 7/19/4		and the second second second second second	temperature(22±3) C and
Calibration Equipment used		calibration)	
numidity<70%. Calibration Equipment used Primary Standards Power Meter NRP2	ID# (calibration) Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration
Calibration Equipment used		calibration)	Scheduled Calibration
Calibration Equipment used Primary Standards Power Meter NRP2	ID# (101919	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447)	Scheduled Calibration Jun-21
Calibration Equipment used rimary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91	ID# (101919 101547	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator	ID # (101919 101547 101548	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23 X01547) 13-Mar-23(CTTL, No.J23 X01548)	Scheduled Calibration Jun-21 Jun-21 Jun-21
Calibration Equipment used rimary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4	ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23X01547) 13-Mar-23(CTTL, No.J23X01548) 26-Sep-22(SPEAG,No.EX3-7433_Sep22)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91	ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23 X01547) 13-Mar-23(CTTL, No.J23 X01548)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21
Calibration Equipment used rimary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4	ID # (101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23X01547) 13-Mar-23(CTTL, No.J23X01548) 26-Sep-22(SPEAG,No.EX3-7433_Sep22)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID #	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23X01547) 13-Mar-23(CTTL, No.J23X01548) 26-Sep-22(SPEAG, No.EX3-7433_Sep22) 13-Dec-22(SPEAG, No.DAE4-549_Dec22)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 7433 SN 549 ID # 6201052605	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23 (CTTL, No.J23 X01547) 13-Mar-23 (CTTL, No.J23 X01548) 26-Sep-22 (SPEAG, No.EX3-7433_Sep22) 13-Dec-22 (SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A Network Analyzer E5071C	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 7433 SN 549 ID # 6201052605	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23X01547) 13-Mar-23(CTTL, No.J23X01548) 26-Sep-22(SPEAG, No.EX3-7433_Sep22) 13-Dec-22(SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.) 27-Jun-22 (CTTL, No.J22X04776)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration Jun-21
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A Network Analyzer E5071C	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605 MY46110673	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23(CTTL, No.J23X01547) 13-Mar-23(CTTL, No.J23X01548) 26-Sep-22(SPEAG,No.EX3-7433_Sep22) 13-Dec-22(SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.) 27-Jun-22 (CTTL, No.J22X04776) 13-Jan-23 (CTTL, No.J23X00285)	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration Jun-21 Jan -22
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A Network Analyzer E5071C Calibrated by:	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605 MY46110673 Name	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23 (CTTL, No.J23 X01547) 13-Mar-23 (CTTL, No.J23 X01548) 26-Sep-22 (SPEAG, No.EX3-7433_Sep22) 13-Dec-22 (SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.) 27-Jun-22 (CTTL, No.J23X00285) Function	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration Jun-21 Jan -22
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A Network Analyzer E5071C Calibrated by: Reviewed by:	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605 MY46110673 Name Yu Zongying	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23 (CTTL, No.J23 X01547) 13-Mar-23 (CTTL, No.J23 X01548) 26-Sep-22 (SPEAG, No.EX3-7433_Sep22) 13-Dec-22 (SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.) 27-Jun-22 (CTTL, No.J23 X00285) Function SAR Test Engineer	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration Jun-21 Jan -22
Calibration Equipment used Primary Standards Power Meter NRP2 Power sensor NRP-Z91 Power sensor NRP-Z91 Reference10dBAttenuator Reference20dBAttenuator Reference Probe EX3DV4 DAE4 Secondary Standards SignalGeneratorMG3700A	ID # 0 101919 101547 101548 18N50W-10dB 18N50W-20dB SN 7433 SN 549 ID # 6201052605 MY46110673 Name Yu Zongying Lin Hao	calibration) Cal Date(Calibrated by, Certificate No.) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 20-Jun-22 (CTTL, No.J22 X07447) 13-Mar-23 (CTTL, No.J23 X01547) 13-Mar-23 (CTTL, No.J23 X01548) 26-Sep-22 (SPEAG, No.EX3-7433_Sep22) 13-Dec-22 (SPEAG, No.DAE4-549_Dec22) Cal Date(Calibrated by, Certificate No.) 27-Jun-22 (CTTL, No.J23X00285) Function SAR Test Engineer SAR Test Engineer	Scheduled Calibration Jun-21 Jun-21 Jun-21 Mar-22 Mar-22 Sep-21 Dec -21 Scheduled Calibration Jun-21 Jan -22 Signature

Certificate No: 723-98671

Page 1 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 39 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConvF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A,B,C,D	modulation dependent linearization parameters
Polarization Φ	Φ rotation around probe axis
Polarization θ	θ rotation around an axis that is in the plane normal to probe axis (at measurement center), i
	$\theta=0$ is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2013, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300MHz to 3GHz)", February 2005
- c) IEC 62209-2, "Procedure to determine the Specific Absorption Rate (SAR) for wireless communication devices used in close proximity to the human body (frequency range of 30 MHz to 6 GHz)", March 2010

d) KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization θ=0 (f≤900MHz in TEM-cell; f>1800MHz: waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E²-field uncertainty inside TSL (see below ConvF).
- NORM(f)x, y, z = NORMx, y, z* frequency_response (see Frequency Response Chart). This
 linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the
 frequency response is included in the stated uncertainty of ConvF.
- DCPx, y, z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics.
- Ax, y, z; Bx, y, z; Cx, y, z; VRx, y, z:A, B, C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters: Assessed in flat phantom using E-field (or Temperature Transfer Standard for f≤800MHz) and inside waveguide using analytical field distributions based on power measurements for f >800MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty valued are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z* ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from±50MHz to±100MHz.
- Spherical isotropy (3D deviation from isotropy): in a field of low gradients realized using a flat
 phantom exposed by a patch antenna.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: Z23-98671

Page 2 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

g

Page 40 of 64



Add: No.51 Xueyuan Road, Tel: +86-10-62304633-2218 E-mail: cttl@chinattl.com

CALIBRATION LABORATORY d, Haidian District, Beijing, 100191, China Fax: +86-10-62304633-2209 Http://www.chinattl.cn

а

pe

Probe EX3DV4

SN: 7396

Calibrated: May 06, 2023

Calibrated for DASY/EASY Systems

(Note: non-compatible with DASY2 system!)

Certificate No: Z23-98671

Page 3 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 41 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing. 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

DASY/EASY - Parameters of Probe: EX3DV4 - SN: 7396

а

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm(µV/(V/m) ²) ^A	0.54	0.53	0.50	±10.0%
DCP(mV) ^B	97.8	104.5	102.5	

Modulation Calibration Parameters

UID	Communication		A	в	С	D	VR	Unc ^E
	System Name		dB	dBõV		dB	mV	(k=2)
0	CW	X	0.0	0.0	1.0	0.00	199.9	±2.4%
		Y	0.0	0.0	1.0		203.3	
		Z	0.0	0.0	1.0		195.0	

The reported uncertainty of measurement is stated as the standard uncertainty of Measurement multiplied by the coverage factor k=2, which for a normal distribution Corresponds to a coverage probability of approximately 95%.

^A The uncertainties of Norm X, Y, Z do not affect the E²-field uncertainty inside TSL (see Page 5 and Page 6). ^B Numerical linearization parameter: uncertainty not required.

^E Uncertainly is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

Certificate No: Z23-98671

Page 4 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-10012

Page 42 of 64



Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2218 Fax: +86-10-62304633-2209 E-mail: cttl@chinattl.com

Http://www.chinattl.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz] ^C	Relative Permittivity ^F	Conductivity (S/m) [⊧]	ConvF X	ConvF Y	ConvF Z	Alpha ^G	Depth ^G (mm)	Unct. (k=2)
750	41.9	0.89	9.82	9.82	9.82	0.30	0.85	\pm 12.1%
835	41.5	0.90	9.71	9.71	9.71	0.15	1.36	±12.1%
900	41.5	0.97	9.87	9.87	9.87	0.16	1.37	±12.1%
1750	40.1	1.37	8.61	8.61	8.61	0.25	1.04	±12.1%
1900	40.0	1.40	8.13	8.13	8.13	0.24	1.01	±12.1%
2100	39.8	1.49	8.14	8.14	8.14	0.24	1.04	±12.1%
2300	39.5	1.67	7.85	7.85	7.85	0.40	0.75	±12.1%
2450	39.2	1.80	7.57	7.57	7.57	0.50	0.75	\pm 12.1%
2600	39.0	1.96	7.38	7.38	7.38	0.64	0.68	±12.1%
5250	35.9	4.71	5.33	5.33	5.33	0.45	1.30	±13.3%
5600	35.5	5.07	4.89	4.89	4.89	0.45	1.35	±13.3%
5750	35.4	5.22	4.92	4.92	4.92	0.45	1.45	±13.3%

^c Frequency validity above 300 MHz of ±100MHz only applies for DASY v4.4 and higher (Page 2), else it is restricted to ±50MHz. The uncertainty is the RSS of ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ± 10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Above 5 GHz frequency validity can be extended to ± 110 MHz.

^F At frequency below 3 GHz, the validity of tissue parameters (ϵ and σ) can be relaxed to ±10% if liquid compensation formula is applied to measured SAR values. At frequencies above 3 GHz, the validity of tissue parameters (ε and σ) is restricted to ±5%. The uncertainty is the RSS of the ConvF uncertainty for indicated target tissue parameters. ^G Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than \pm 1% for frequencies below 3 GHz and below \pm 2% for the frequencies between 3-6 GHz at any distance larger than half the probe tip diameter from the boundary.

Certificate No: Z23-98671

Page 5 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-100124

Page 43 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz] ^C	Relative Permittivity ^F	Conductivity (S/m) [⊦]	ConvF X	ConvF Y	ConvF Z	Alpha ^G	Depth ^G (mm)	Unct. (k=2)
750	55.5	0.96	10.09	10.09	10.09	0.30	0.90	±12.1%
835	55.2	0.97	9.88	9.88	9.88	0.19	1.32	±12.1%
900	55.0	1.05	9.82	9.82	9.82	0.23	1.15	±12.1%
1750	53.4	1.49	8.24	8.24	8.24	0.24	1.06	±12.1%
1900	53.3	1.52	7.97	7.97	7.97	0.19	1.24	±12.1%
2100	53.2	1.62	8.18	8.18	8.18	0.19	1.39	±12.1%
2300	52.9	1.81	7.88	7.88	7.88	0.55	0.80	±12.1%
2450	52.7	1.95	7.53	7.53	7.53	0.46	0.89	±12.1%
2600	52.5	2.16	7.38	7.38	7.38	0.52	0.80	±12.1%
5250	48.9	5.36	4.93	4.93	4.93	0.45	1.80	±13.3%
5600	48.5	5.77	4.19	4.19	4.19	0.48	1.90	±13.3%
5750	48.3	5.94	4.52	4.52	4.52	0.48	1.95	±13.3%

^C Frequency validity above 300 MHz of ±100MHz only applies for DASY v4.4 and higher (Page 2), else it is restricted to ±50MHz. The uncertainty is the RSS of ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ± 10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Above 5 GHz frequency validity can be extended to ± 110 MHz.

^F At frequency below 3 GHz, the validity of tissue parameters (ε and σ) can be relaxed to ±10% if liquid compensation formula is applied to measured SAR values. At frequencies above 3 GHz, the validity of tissue parameters (ε and σ) is restricted to ±5%. The uncertainty is the RSS of the ConvF uncertainty for indicated target tissue parameters. ^G Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than ± 1% for frequencies below 3 GHz and below ± 2% for the frequencies between 3-6 GHz at any distance larger than half the probe tip diameter from the boundary.

Certificate No: Z23-98671

Page 6 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 44 of 64

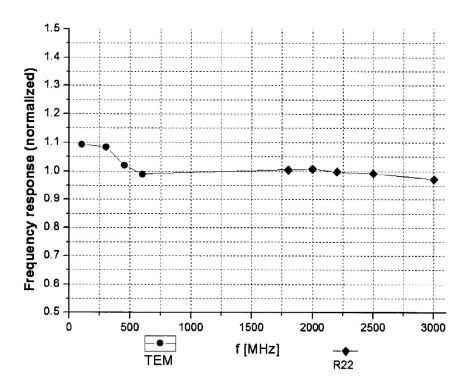


 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

Frequency Response of E-Field (TEM-Cell: ifi110 EXX, Waveguide: R22)



Uncertainty of Frequency Response of E-field: ±7.4% (k=2)

Certificate No: Z23-98671

Page 7 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012/

Page 45 of 64



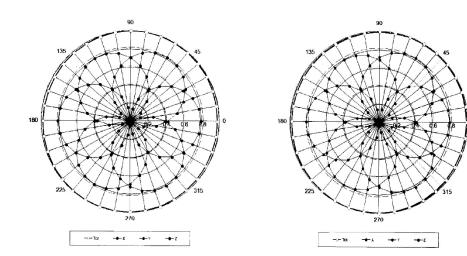
Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2218 Fax: +86-10-62304633-2209 E-mail: cttl@chinattl.com

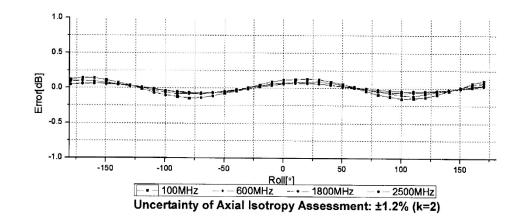
Http://www.chinattl.cn

Receiving Pattern (Φ), θ=0°

f=600 MHz, TEM







Certificate No: Z23-98671

Page 8 of 11

Shenzhen Anbotek Compliance Laboratory Limited

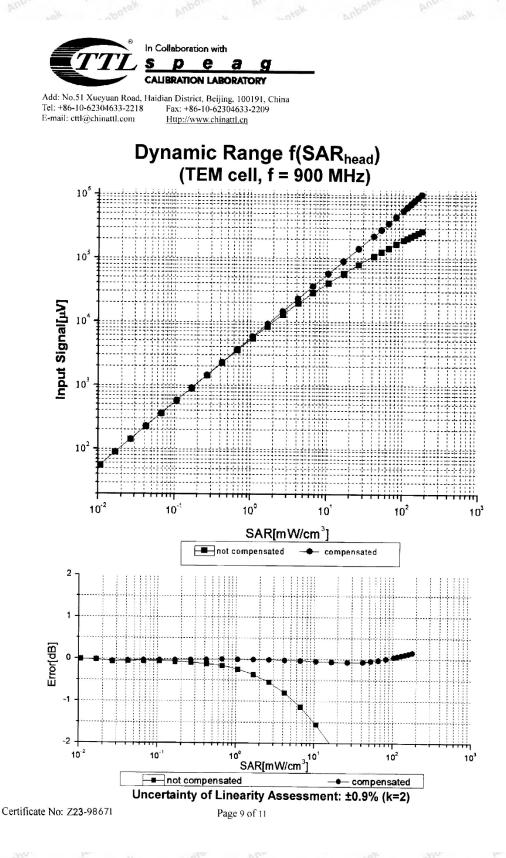
Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 46 of 64



Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 47 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

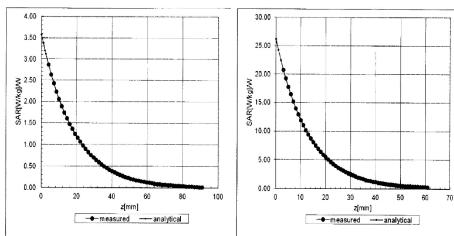
 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

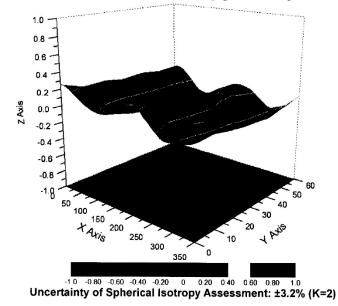
Conversion Factor Assessment

f=900 MHz, WGLS R9(H_convF)

f=1750 MHz, WGLS R22(H_convF)



Deviation from Isotropy in Liquid



Certificate No: Z23-98671

Page 10 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 48 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: ettl@chinattl.com
 <u>Http://www.chinattl.cn</u>

DASY/EASY - Parameters of Probe: EX3DV4 - SN: 7396

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	156.9
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disable
Probe Overall Length	337mm
Probe Body Diameter	10mm
Tip Length	9mm
Tip Diameter	2.5mm
Probe Tip to Sensor X Calibration Point	1mm
Probe Tip to Sensor Y Calibration Point	1mm
Probe Tip to Sensor Z Calibration Point	1mm
Recommended Measurement Distance from Surface	1.4mm

Certificate No: Z23-98671

Page 11 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





 Object
 D2450V2 - SN: 910

 Calibration Procedure(s)
 FD-Z21-2-003-01

 Calibration Procedures for dipole validation kits

Jun 15, 2021

Calibration date:

This calibration Certificate documents the traceability to national standards, which realize the physical units of measurements(SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature(22±3) $^{\circ}$ C and humidity<70%.

Calibration Equipment used (M&TE critical for calibration)

1919 1547 7307 771 # (49071430 (46110673	01-Jul-20 (CTTL, No.J20X04256) 01-Jul-20 (CTTL, No.J20X04256) 19-Feb-21(SPEAG,No.EX3-7307_Feb21) 02-Feb-21(CTTL-SPEAG,No.Z21-97011) Cal Date(Calibrated by, Certificate No.) 01-Feb-21 (CTTL, No.J18X00893) 26-Jan-21 (CTTL, No.J18X00894)	Jun-21 Jun-21 Feb-22 Feb-22 Scheduled Calibration Jan-22
7307 771 # 49071430	19-Feb-21(SPEAG,No.EX3-7307_Feb21) 02-Feb-21(CTTL-SPEAG,No.Z21-97011) Cal Date(Calibrated by, Certificate No.) 01-Feb-21 (CTTL, No.J18X00893)	Feb-22 Feb-22 Scheduled Calibration
771 # 49071430	02-Feb-21(CTTL-SPEAG,No.Z21-97011) Cal Date(Calibrated by, Certificate No.) 01-Feb-21 (CTTL, No.J18X00893)	Feb-22 Scheduled Calibration
# ′49071430	Cal Date(Calibrated by, Certificate No.) 01-Feb-21 (CTTL, No.J18X00893)	Scheduled Calibration
49071430	01-Feb-21 (CTTL, No.J18X00893)	
		Jan-22
46110673	26- Jan-21 (CTTL No. 118X00894)	
	20-041-21 (0112, 10.010,00004)	Jan-22
ime	Function	Signature
o Jing	SAR Test Engineer	State -
Dianyuan	SAR Project Leader	too
Bingsong	Deputy Director of the laboratory	In usita
	Issued: Jun 1	7, 2021
	lianyuan	ianyuan SAR Project Leader

Certificate No: Z21-97091

Page 1 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com

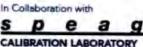






FCC ID:A4C-10012A

Page 50 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2079
 Fax: +86-10-62304633-2504

 E-mail: cttl@chinattl.com
 Http://www.chinattl.cn

Glossary: TSL

ConvF

N/A

tissue simulating liquid sensitivity in TSL / NORMx,y,z not applicable or not measured

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2013, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) For hand-held devices used in close proximity to the ear (frequency range of 300MHz to 3GHz)", February 2005
- c) IEC 62209-2, "Procedure to measure the Specific Absorption Rate (SAR) For wireless communication devices used in close proximity to the human body (frequency range of 30MHz to 6GHz)", March 2010
- d) KDB865664, SAR Measurement Requirements for 100 MHz to 6 GHz

Additional Documentation:

e) DASY4/5 System Handbook

Methods Applied and Interpretation of Parameters:

- Measurement Conditions: Further details are available from the Validation Report at the end
 of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- Antenna Parameters with TSL: The dipole is mounted with the spacer to position its feed
 point exactly below the center marking of the flat phantom section, with the arms oriented
 parallel to the body axis.
- Feed Point Impedance and Return Loss: These parameters are measured with the dipole
 positioned under the liquid filled phantom. The impedance stated is transformed from the
 measurement at the SMA connector to the feed point. The Return Loss ensures low
 reflected power. No uncertainty required.
- Electrical Delay: One-way delay between the SMA connector and the antenna feed point. No uncertainty required.
- SAR measured: SAR measured at the stated antenna input power.
- SAR normalized: SAR as measured, normalized to an input power of 1 W at the antenna connector.
- SAR for nominal TSL parameters: The measured TSL parameters are used to calculate the nominal SAR result.

The reported uncertainty of measurement is stated as the standard uncertainty of Measurement multiplied by the coverage factor k=2, which for a normal distribution Corresponds to a coverage probability of approximately 95%.

Certificate No: Z18-9709)

Page 2 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com



Anbotek Product Safety



FCC ID:A4C-10012A





 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2079
 Fax: +86-10-62304633-2504

 E-mail: ctl@chinattl.com
 Http://www.chinattl.en

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY52	52.8.8.1258
Extrapolation	Advanced Extrapolation	
Phantom	Triple Flat Phantom 5.1C	
Distance Dipole Center - TSL	10 mm	with Spacer
Zoom Scan Resolution	dx, dy, dz = 5 mm	
Frequency	2450 MHz ± 1 MHz	

Head TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Head TSL parameters	22.0 °C	39.2	1.80 mho/m
Measured Head TSL parameters	(22.0 ± 0.2) °C	39.0 ± 6 %	1.77 mho/m ± 6 %
Head TSL temperature change during test	<1.0 °C		-

SAR result with Head TSL

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR measured	250 mW input power	13.0 mW / g
SAR for nominal Head TSL parameters	normalized to 1W	52.4 mW /g ± 20.8 % (k=2)
SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	1.000
SAR measured	250 mW input power	6.06 mW / g
SAR for nominal Head TSL parameters	normalized to 1W	24.3 mW /g ± 20.4 % (k=2)

Body TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Body TSL parameters	22.0 °C	52.7	1.95 mho/m
Measured Body TSL parameters	(22.0 ± 0.2) °C	52.9 ± 6 %	1.97 mho/m ± 6 %
Body TSL temperature change during test	<1.0 °C		

SAR result with Body TSL

SAR averaged over 1 cm ³ (1 g) of Body TSL	Condition	
SAR measured	250 mW input power	13.0 mW/g
SAR for nominal Body TSL parameters	normalized to 1W	51.8 mW /g ± 20.8 % (k=2)
SAR averaged over 10 cm^3 (10 g) of Body TSL	Condition	
SAR measured	250 mW input power	6.18 mW/g
SAR for nominal Body TSL parameters	normalized to 1W	24.7 mW /g ± 20.4 % (k=2)

Certificate No: Z18-97091

Page 3 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 52 of 64



Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2079 Fax: +86-10-62304633-2504 E-mail: ettl@chinattl.com Http://www.ebinattl.cn

Appendix

Antenna Parameters with Head TSL

Impedance, transformed to feed point	54.6Ω+ 2.77jΩ	
Return Loss	- 25.8dB	

Antenna Parameters with Body TSL

Impedance, transformed to feed point	50.7Ω+ 4.28jΩ	
Return Loss	~ 27.3dB	

General Antenna Parameters and Design

3 ns
1.20

After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard. No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by	SPEAG

Certificate No: Z18-97091

Page 4 of 8

Shenzhen Anbotek Compliance Laboratory Limited

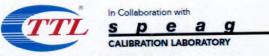
Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 53 of 64



Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2079 E-mail: cttl@chinattl.com

Date: 06.15.2021

DASY5 Validation Report for Head TSL Test Laboratory: CTTL, Beijing, China DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN: 910 Communication System: UID 0, CW; Frequency: 2450 MHz; Duty Cycle: 1:1 Medium parameters used: f = 2450 MHz; $\sigma = 1.767$ S/m; $\epsilon r = 39.01$; $\rho = 1000$ kg/m3 Phantom section: Right Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2007)

Fax: +86-10-62304633-2504

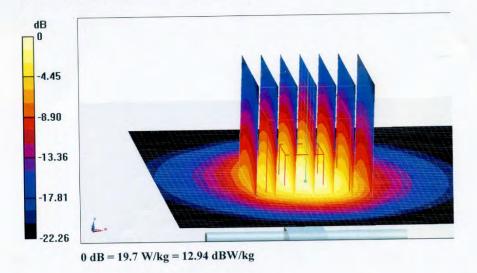
Http://www.chinattl.cn

DASY5 Configuration:

- Probe: EX3DV4 SN7307; ConvF(7.36, 7.36, 7.36); Calibrated: 2/19/2021; .
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn771; Calibrated: 2021-02-02
- Phantom: Triple Flat Phantom 5.1C; Type: QD 000 P51 CA; Serial: 1161/1
- Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7372)

Dipole Calibration/Zoom Scan (7x7x7) (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 106.5 V/m; Power Drift = 0.02 dB Peak SAR (extrapolated) = 26.7 W/kg SAR(1 g) = 13 W/kg; SAR(10 g) = 6.06 W/kg Maximum value of SAR (measured) = 19.7 W/kg



Certificate No: Z21-97091

Page 5 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





Report No.: 18220WC30188001 FCC ID:A4C-10012A Page 54 of 64

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 55 of 64

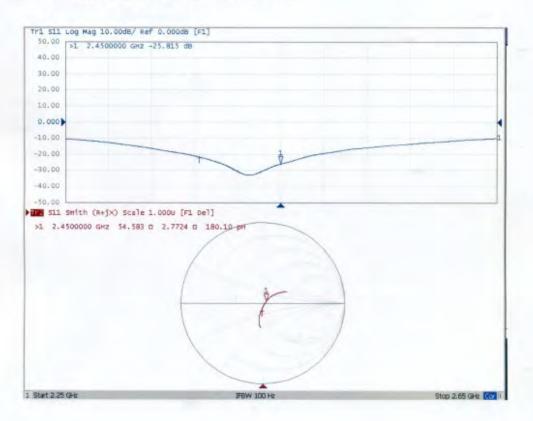


 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2079
 Fax: +86-10-62304633-2504

 E-mail: cttl@chinattl.com
 Http://www.chinattl.cn

Impedance Measurement Plot for Head TSL



Certificate No: Z18-97091

Page 6 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 56 of 64



 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2079
 Fax: +86-10-62304633-2504

 E-mail: cttl@chinattl.com
 Http://www.chinattl.cn

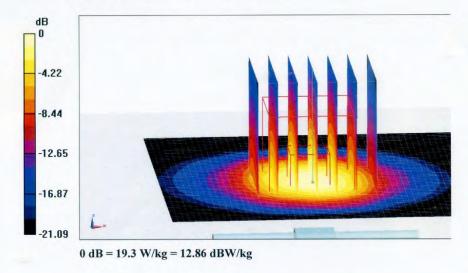
Date: 06.15.2021

DASY5 Validation Report for Body TSL Test Laboratory: CTTL, Beijing, China DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN: 910 Communication System: UID 0, CW; Frequency: 2450 MHz; Duty Cycle: 1:1 Medium parameters used: f = 2450 MHz; $\sigma = 1.972 \text{ S/m}$; $\varepsilon_r = 52.92$; $\rho = 1000 \text{ kg/m}^3$ Phantom section: Center Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2007) DASY5 Configuration:

- Probe: EX3DV4 SN7307; ConvF(7.22, 7.22, 7.22); Calibrated: 2/19/2021; .
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn771; Calibrated: 2021-02-02
- Phantom: Triple Flat Phantom 5.1C; Type: QD 000 P51 CA; Serial: 1161/1
- Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7372)

Dipole Calibration/Zoom Scan (7x7x7) (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 98.89 V/m; Power Drift = 0.03 dB Peak SAR (extrapolated) = 25.6 W/kg SAR(1 g) = 13 W/kg; SAR(10 g) = 6.18 W/kg Maximum value of SAR (measured) = 19.3 W/kg



Certificate No: Z21-97091

Page 7 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotek.com





FCC ID:A4C-10012A





 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, (

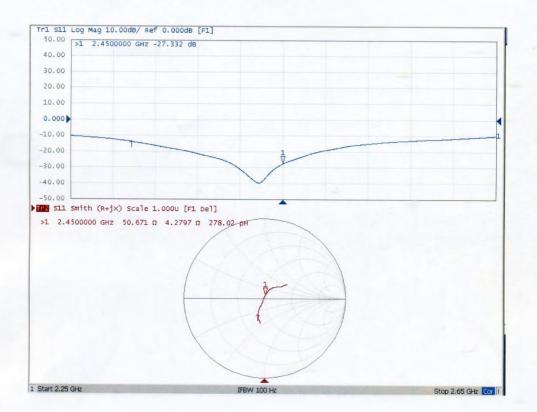
 Tel: +86-10-62304633-2079

 Fax: +86-10-62304633-2079

 Fax: +86-10-62304633-2079

 Http://www.chinattl.cn

Impedance Measurement Plot for Body TSL



Certificate No: Z21-97091

Page 8 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 58 of 64

Schmid & Partner Engineering AG

speag

Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com

IMPORTANT NOTICE

USAGE OF THE DAE 4

The DAE unit is a delicate, high precision instrument and requires careful treatment by the user. There are no serviceable parts inside the DAE. Special attention shall be given to the following points:

Battery Exchange: The battery cover of the DAE4 unit is closed using a screw, over tightening the screw may cause the threads inside the DAE to wear out.

Shipping of the DAE: Before shipping the DAE to SPEAG for calibration, remove the batteries and pack the DAE in an antistatic bag. This antistatic bag shall then be packed into a larger box or container which protects the DAE from impacts during transportation. The package shall be marked to indicate that a fragile instrument is inside.

E-Stop Failures Touch detection may be malfunctioning due to broken magnets in the E-stop. Rough handling of the E-stop may lead to damage of these magnets. Touch and collision errors are often caused by dust and dirt accumulated in the E-stop. To prevent E-stop failure, the customer shall always mount the probe to the DAE carefully and keep the DAE unit in a non-dusty environment if not used for measurements.

Repair: Minor repairs are performed at no extra cost during the annual calibration. However, SPEAG reserves the right to charge for any repair especially if rough unprofessional handling caused the defect.

DASY Configuration Files: Since the exact values of the DAE input resistances, as measured during the calibration procedure of a DAE unit, are not used by the DASY software, a nominal value of 200 MOhm is given in the corresponding configuration file.

Important Note:

Warranty and calibration is void if the DAE unit is disassembled partly or fully by the Customer.

Important Note:

Never attempt to grease or oil the E-stop assembly. Cleaning and readjusting of the Estop assembly is allowed by certified SPEAG personnel only and is part of the annual calibration procedure.

Important Note:

To prevent damage of the DAE probe connector pins, use great care when installing the probe to the DAE. Carefully connect the probe with the connector notch oriented in the mating position. Avoid any rotational movement of the probe body versus the DAE while turning the locking nut of the connector. The same care shall be used when disconnecting the probe from the DAE.

Schmid & Partner Engineering

TN_BR040315AD DAE4.doc

11.12.2009

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 59 of 64

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

S

C

S

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client Anbotek (Auden)

Certificate No: DAE4-387_Sep10

Object	DAE4 - SD 000 D	04 BM - SN: 387	
Calibration procedure(s)	QA CAL-06.v29	dure for the data acquisition ele	
	Calibration proces		ctronics (DAE)
Calibration date:	September 06, 20	22	
This calibration certificate docum	ents the traceability to natio	nal standards, which realize the physical un	nits of measurements (SI).
he measurements and the unce	mainues with confidence pro	obability are given on the following pages a	nd are part of the certificate.
Il calibrations have been condu	cted in the closed laboratory	facility: environment temperature (22 \pm 3)°	°C and humidity < 70%.
alibration Equipment used (M&	TE critical for calibration)		
	TE critical for calibration)	Cal Date (Certificate No.)	Scheduled Calibration
rimary Standards		Cal Date (Certificate No.) 15-Aug-21 (No:22092)	Scheduled Calibration Aug-22
Primary Standards Keithley Multimeter Type 2001	ID #		
rimary Standards eithley Multimeter Type 2001 econdary Standards uto DAE Calibration Unit	ID # SN: 0810278 ID # SE UWS 053 AA 1001	15-Aug-21 (No:22092) Check Date (in house) 05-Jan-22 (in house check)	Aug-22 Scheduled Check In house check: Jan-23
Calibration Equipment used (M& Primary Standards Keithley Multimeter Type 2001 Secondary Standards Auto DAE Calibration Unit Calibrator Box V2.1	ID # SN: 0810278 ID # SE UWS 053 AA 1001	15-Aug-21 (No:22092) Check Date (in house)	Aug-22 Scheduled Check
Primary Standards Keithley Multimeter Type 2001 Secondary Standards Nuto DAE Calibration Unit	ID # SN: 0810278 ID # SE UWS 053 AA 1001	15-Aug-21 (No:22092) Check Date (in house) 05-Jan-22 (in house check)	Aug-22 Scheduled Check In house check: Jan-23
Primary Standards Keithley Multimeter Type 2001 Secondary Standards Nuto DAE Calibration Unit	ID # SN: 0810278 ID # SE UWS 053 AA 1001	15-Aug-21 (No:22092) Check Date (in house) 05-Jan-22 (in house check)	Aug-22 Scheduled Check In house check: Jan-23
Primary Standards Keithley Multimeter Type 2001 Secondary Standards Nuto DAE Calibration Unit Calibrator Box V2.1	ID # SN: 0810278 ID # SE UWS 053 AA 1001 SE UMS 006 AA 1002	15-Aug-21 (No:22092) Check Date (in house) 05-Jan-22 (in house check) 05-Jan-22 (in house check)	Aug-22 Scheduled Check In house check: Jan-23 In house check: Jan-23 Signature
Primary Standards Keithley Multimeter Type 2001 Secondary Standards Auto DAE Calibration Unit	ID # SN: 0810278 ID # SE UWS 053 AA 1001 SE UMS 006 AA 1002	15-Aug-21 (No:22092) Check Date (in house) 05-Jan-22 (in house check) 05-Jan-22 (in house check) Function	Aug-22 Scheduled Check In house check: Jan-23 In house check: Jan-23

Certificate No: DAE4-387_Sep10

Page 1 of 5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 60 of 64

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst Service sulsse d'étalonnage

- C Service suisse d'étalonnage Servizio svizzero di taratura
 - Swiss Calibration Service

S

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA. Multilateral Agreement for the recognition of calibration certificates

Glossary

DAE Connector angle data acquisition electronics information used in DASY system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters

- DC Voltage Measurement: Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- Connector angle: The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters as documented in the Appendix contain technical information as a result from the performance test and require no uncertainty.
 - DC Voltage Measurement Linearity: Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
 - Common mode sensitivity: Influence of a positive or negative common mode voltage on the differential measurement.
 - Channel separation: Influence of a voltage on the neighbor channels not subject to an input voltage.
 - AD Converter Values with inputs shorted: Values on the internal AD converter corresponding to zero input voltage
 - Input Offset Measurement. Output voltage and statistical results over a large number of zero voltage measurements.
 - Input Offset Current: Typical value for information; Maximum channel input offset current, not considering the input resistance.
 - Input resistance: Typical value for information: DAE input resistance at the connector, during internal auto-zeroing and during measurement.
 - Low Battery Alarm Voltage: Typical value for information. Below this voltage, a battery alarm signal is generated.
 - Power consumption: Typical value for information. Supply currents in various operating modes.

Certificate No: DAE4-387_Sep10

Page 2 of 5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 61 of 64

DC Voltage Measurement

A/D - Converte	Resolution	nominal
----------------	------------	---------

High Range:	1LSB =	6.1µV,	full range =	-100+300 mV
Low Range:	1LSB =	61nV,	full range =	-1+3mV
DASY measurement	parameters: Aut	o Zero Time: 3	sec; Measuring	time: 3 sec

Calibration Factors	x	Y	Z
High Range	404.489 ± 0.02% (k=2)	404.852 ± 0.02% (k=2)	404.862 ± 0.02% (k=2)
Low Range	3.97827 ± 1.50% (k=2)	3.95875 ± 1.50% (k=2)	3.97982 ± 1.50% (k=2)

Connector Angle

Connector Angle to be used in DASY system	53.0 ° ± 1 °

Page 3 of 5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Appendix (Additional assessments outside the scope of SCS0108)

1. DC Voltage Linearity

High Range	Reading (µV)	Difference (µV)	Error (%)
Channel X + Input	200032.85	-3.31	-0.00
Channel X + Input	20007.64	1.88	0.01
Channel X - Input	-20003.48	1.18	-0.01
Channel Y + Input	200034.23	-1.43	-0.00
Channel Y + Input	20006.60	0.91	0.00
Channel Y - Input	-20004.04	0.72	-0.00
Channel Z + Input	200035.38	-0.83	-0.00
Channel Z + Input	20003.69	-2.11	-0.01
Channel Z - Input	-20006.38	-1.59	0.01

Low Range	Reading (µV)	Difference (µV)	Error (%)
Channel X + Input	2001.63	0.08	0.00
Channel X + Input	202.29	0.70	0.35
Channel X - Input	-197.90	0.60	-0.30
Channel Y + Input	2001.33	-0.07	-0.00
Channel Y + Input	200.86	-0.60	-0.30
Channel Y - Input	-199.87	-1.23	0.62
Channel Z + Input	2001.61	0.27	0.01
Channel Z + Input	200.60	-0.70	-0.35
Channel Z - Input	-199.51	-0.85	0.43

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (μV)	Low Range Average Reading (µV)
Channel X	200	13.50	11.56
	- 200	-8.64	-11.18
Channel Y	200	-0.81	-1.28
	- 200	1.05	0.09
Channel Z	200	7.17	6.91
	- 200	-9.46	-9.01

3. Channel separation

DASY measurement parameters: Auto Zero	Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (µV)	Channel Y (µV)	Channel Z (µV)
Channel X	200	-	-1.70	0.33
Channel Y	200	10.70	-	-0.38
Channel Z	200	7.11	7.89	-

Certificate No: DAE4-387_Sep10

Page 4 of 5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





Page 63 of 64

4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB) 17466	
Channel X	15969		
Channel Y	15661	16162	
Channel Z	15990	16190	

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec Input $10M\Omega$

	Average (µV)	min. Offset (μV)	max. Offset (μV)	Std. Deviation (µV)
Channel X	0.73	-2.58	3.29	0.62
Channel Y	0.41	-0.49	1.23	0.40
Channel Z	-0.80	-1.88	0.30	0.42

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance (Typical values for information)

	Zeroing (kOhm)	Measuring (MOhm)	
Channel X	200	200	
Channel Y	200	200	
Channel Z	200	200	

8. Low Battery Alarm Voltage (Typical values for information)

Typical values	Alarm Level (VDC)	
Supply (+ Vcc)	+7.9	
Supply (- Vcc)	-7.6	

9. Power Consumption (Typical values for information)

Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA) +14	
Supply (+ Vcc)	+0.01	+6		
Supply (- Vcc)	-0.01	-8	-9	

Certificate No: DAE4-387_Sep10

Page 5 of 5

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com





FCC ID:A4C-10012A

Page 64 of 64

			Head			
Date of Measurement	Return-Loss (dB)	Delta (%)	Real Impedance (ohm)	Delta (ohm)	Imaginary Impedance (johm)	Delta (johm)
2021-06-15	-25.8	I wote	54.6	Par 1 Mar	2.77	anyou
2022-06-14	-26.10	1.10%	54.293	-0.29	3.39	-0.62
2023-06-13	-26.18	1.40%	54.403	-0.18	3.05	-0.28

Justification of Extended Calibration SAR Dipole D2450V2- serial no. 910

Pa	-16" A1	<u>, 0</u>	Body	90° P		
Date of Measurement	Return-Loss (dB)	Delta (%)	Real Impedance (ohm)	Delta (ohm)	Imaginary Impedance (johm)	Delta (johm)
2021-06-15	-27.3	ek / pubo	50.7	ok / unbo	4.28	x 1
2022-06-14	-27.39	0.20%	50.511	-0.16	4.51	-0.23
2023-06-13	-27.63	1.10%	49.971	-0.7	4.41	-0.13

*****END OF REPORT*****

Shenzhen Anbotek Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 0755–26066440 Fax:(86) 0755–26014772 Email:service@anbotek.com

